



ISBN 978 3 901906 73 2

COMMISSION INTERNATIONALE DE L'ECLAIRAGE
INTERNATIONAL COMMISSION ON ILLUMINATION
INTERNATIONALE BELEUCHTUNGSKOMMISSION

**PROCEEDINGS of the
CIE Expert Symposium on**

**Advances in
Photometry and Colorimetry**

7-8 July 2008

**Hotel Concorde
Turin, Italy**

CIE x033:2008

CD-ROM INCLUDED

THE INTERNATIONAL COMMISSION ON ILLUMINATION

The International Commission on Illumination (CIE) is an organisation devoted to international co-operation and exchange of information among its member countries on all matters relating to the art and science of lighting. Its membership consists of the National Committees in about 40 countries.

The objectives of the CIE are:

1. To provide an international forum for the discussion of all matters relating to the science, technology and art in the fields of light and lighting and for the interchange of information in these fields between countries.
2. To develop basic standards and procedures of metrology in the fields of light and lighting.
3. To provide guidance in the application of principles and procedures in the development of international and national standards in the fields of light and lighting.
4. To prepare and publish standards, reports and other publications concerned with all matters relating to the science, technology and art in the fields of light and lighting.
5. To maintain liaison and technical interaction with other international organisations concerned with matters related to the science, technology, standardisation and art in the fields of light and lighting.

The work of the CIE is carried on by seven Divisions each with about 20 Technical Committees. This work covers subjects ranging from fundamental matters to all types of lighting applications. The standards and technical reports developed by these international Divisions of the CIE are accepted throughout the world.

A plenary session is held every four years, at which the work of the Divisions and Technical Committees is reviewed, reported and plans are made for the future. The CIE is recognised as the authority on all aspects of light and lighting, such it occupies an important position among international organisations.

LA COMMISSION INTERNATIONALE DE L'ECLAIRAGE

La Commission Internationale de l'Eclairage (CIE) est une organisation qui se donne pour but la coopération internationale et l'échange d'informations entre les Pays membres sur toutes les questions relatives à l'art et à la science de l'éclairage. Elle est composée de Comités Nationaux représentant environ 40 pays.

Les objectifs de la CIE sont :

1. De constituer un centre d'étude international pour toute matière relevant de la science, de la technologie et de l'art de la lumière et de l'éclairage et pour l'échange entre pays d'informations dans ces domaines.
2. D'élaborer des normes et des méthodes de base pour la métrologie dans les domaines de la lumière et de l'éclairage.
3. De donner des directives pour l'application des principes et des méthodes d'élaboration de normes internationales et nationales dans les domaines de la lumière et de l'éclairage.
4. De préparer et publier des normes, rapports et autres textes, concernant toutes matières relatives à la science, la technologie et l'art dans les domaines de la lumière et de l'éclairage.
5. De maintenir une liaison et une collaboration technique avec les autres organisations internationales concernées par des sujets relatifs à la science, la technologie, la normalisation et l'art dans les domaines de la lumière et de l'éclairage.

Les travaux de la CIE sont effectués par 7 Divisions, ayant chacune environ 20 Comités Techniques. Les sujets d'études s'étendent des questions fondamentales, à tous les types d'applications de l'éclairage. Les normes et les rapports techniques élaborés par ces Divisions Internationales de la CIE sont reconnus dans le monde entier.

Tous les quatre ans, une Session plénière passe en revue le travail des Divisions et des Comités Techniques, en fait rapport et établit les projets de travaux pour l'avenir. La CIE est reconnue comme la plus haute autorité en ce qui concerne tous les aspects de la lumière et de l'éclairage. Elle occupe comme telle une position importante parmi les organisations internationales.

DIE INTERNATIONALE BELEUCHTUNGSKOMMISSION

Die Internationale Beleuchtungskommission (CIE) ist eine Organisation, die sich der internationalen Zusammenarbeit und dem Austausch von Informationen zwischen ihren Mitgliedsländern bezüglich der Kunst und Wissenschaft der Lichttechnik widmet. Die Mitgliedschaft besteht aus den Nationalen Komitees in rund 40 Ländern.

Die Ziele der CIE sind:

1. Ein internationaler Mittelpunkt für Diskussionen aller Fragen auf dem Gebiet der Wissenschaft, Technik und Kunst der Lichttechnik und für den Informationsaustausch auf diesen Gebieten zwischen den einzelnen Ländern zu sein.
2. Grundnormen und Verfahren der Meßtechnik auf dem Gebiet der Lichttechnik zu entwickeln.
3. Richtlinien für die Anwendung von Prinzipien und Vorgängen in der Entwicklung internationaler und nationaler Normen auf dem Gebiet der Lichttechnik zu erstellen.
4. Normen, Berichte und andere Publikationen zu erstellen und zu veröffentlichen, die alle Fragen auf dem Gebiet der Wissenschaft, Technik und Kunst der Lichttechnik betreffen.
5. Liaison und technische Zusammenarbeit mit anderen internationalen Organisationen zu unterhalten, die mit Fragen der Wissenschaft, Technik, Normung und Kunst auf dem Gebiet der Lichttechnik zu tun haben.

Die Arbeit der CIE wird in 7 Divisionen, jede mit etwa 20 Technischen Komitees, geleistet. Diese Arbeit betrifft Gebiete mit grundlegendem Inhalt bis zu allen Arten der Lichtenwendung. Die Normen und Technischen Berichte, die von diesen international zusammengesetzten Divisionen ausgearbeitet werden, sind von der ganzen Welt anerkannt.

Tagungen werden alle vier Jahre abgehalten, in der die Arbeiten der Divisionen überprüft und berichtet und neue Pläne für die Zukunft ausgearbeitet werden. Die CIE wird als höchste Autorität für alle Aspekte des Lichtes und der Beleuchtung angesehen. Auf diese Weise unterhält sie eine bedeutende Stellung unter den internationalen Organisationen.

Published by the

COMMISSION INTERNATIONALE DE L'ECLAIRAGE
CIE Central Bureau
Kegelgasse 27, A-1030 Vienna, AUSTRIA
Tel: +43 1 714 31 87 0, Fax: +43 1 714 31 87 18
e-mail: ciecb@cie.co.at
WWW: <http://www.cie.co.at/>



ISBN 978 3 901906 73 2

COMMISSION INTERNATIONALE DE L'ECLAIRAGE
INTERNATIONAL COMMISSION ON ILLUMINATION
INTERNATIONALE BELEUCHTUNGSKOMMISSION

**PROCEEDINGS of the
CIE Expert Symposium on**

**Advances in
Photometry and Colorimetry**

7-8 July 2008

**Hotel Concord
Turin, Italy**

CIE x033:2008

CD-ROM INCLUDED



CIE EXPERT SYMPOSIUM on
Advances in Photometry and Colorimetry

co-hosted by the Istituto Nazionale di Ricerca Metrologica
and
Commission Internationale de l'Eclairage

CIE thanks Everfine, LMT, Radiant Imaging and TechnoTeam Bildverarbeitung GmbH for their generous sponsorship of this CIE Symposium



Since 1993



<http://www.lmt.de>



Symposium Co-Chairs

Yoshi Ohno
National Institute of Standards and Technology, Gaithersburg, MD, USA
e-mail: ohno@nist.gov Tel. +1 301 975 2321

Maria Luisa Rastello
National Research Institute of Metrology (INRiM), Torino, Italy
e-mail: m.rastello@inrim.it Tel. + 39 011 39 19 219

Organizing Committee

Martina Paul, Maria Luisa Rastello, Yoshi Ohno, Armin Sperling, Georg Sauter,
Norbert Johnson, Guy Vandermeersch, Jim Gardner, Peter Blattner

Symposium Secretariat

Elisabetta Melli
Istituto Nazionale di Ricerca Metrologica (I.N.R.I.M.)
Settore Biblioteca, Pubblicazioni e Stampa
Strada delle Cacce, 91, 10135 Torino, Italy
e-mail: e.melli@inrim.it Tel. +39 011 3919 524 Fax +39 011 34 63 84

Any mention of organisations or products does not imply endorsement by the CIE. Whilst every care has been taken in the compilation of any list, up to the time of going to press, these may not be comprehensive.

© CIE 2008

All rights reserved. Unless otherwise specified, no part of this publication may be reproduced or utilized in any form or by any means, electronic or mechanical, including photocopying and microfilm, without the permission in writing from the CIE Central Bureau at the address below.

Commission Internationale de l'Eclairage
CIE Central Bureau
Kegelgasse 27
A-1030 Vienna
AUSTRIA

Tel.: +43 1 714 31 87 0
Fax: +43 1 714 31 87 10
e-mail: ciecb@cie.ch
WWW: <http://www.cie.ch/>



Expert Symposium 2008 Advances in Photometry and Colorimetry

Contents

The following table provides an overview of the Symposium Programme. Invited papers are listed in **bold**. The papers are published in the Proceedings in consecutive order of presentation.

Authors	Title	Page
Key Note Paper		
Georg Sauter	Goniophotometry: New challenges and novel solutions	VIII
Session I		
Imaging Photometers and Colorimeters Session Chair: M.L. Rastello		
F. Schmidt, U. Krüger	Image Luminance and Color Measuring Devices	1
R. Rykowski, D. Kreysar	Comparison of Various Methods to Measure Luminous Intensity with an Imaging Colorimeter	9
A. Zschenker, A. Sperling, F. Schmidt, U. Krüger	Determination of the Quality Index "Nonlinearity" of Imaging Luminance Measurement Devices (ILMD)	15
Zs. Kosztyán, S. Sturm, D. Müller, J. Schanda	Decreasing Colour Measuring Systematic Error in Image Taking Tristimulus Colorimeters	21
C.C. Miller	Retro-reflection Measurements using an Imaging Photometer	26
N. Bo P. Iacomussi, G. Rossi	CCD Detectors for Diffusing Material and Retroreflector Characterization	32
Session II		
Spectral Responsivity Measurement and f_1' of Photometers Session Chair: P. Blattner		
J. Pan, H. Cheng, Y. Zong, T. Ohno	f_1' Evaluation and Measurement Comparison	38
J. Novas, A. Sperling, S. Winter, A.E. Abd El Mageed, P. Blattner	Measurements of the Spectral Responsivity and f_1' Values of Photometers	44
U. Krüger, P. Blattner	The Influence of the Uncertainty of the Spectral Responsivity Measurement on the Method of Determination of f_1'	49
E. Ikonen, T. Poikonen, P. Kärhä, P. Manninen, F. Manoocheri	Determination of f_1' and its Uncertainty with Biased and Random Error Models	55

Authors	Title	Page
D.-H. Lee, S. Park, S.N. Park	Spatially Resolved Measurement of Spectral Responsivity of a Photometer with a Mosaic-Type $V(\lambda)$ -Filter	61
K. Muray	Blue LED Measurements	64
M.D. Lysko	Quality Matching of the $V(\lambda)$ -Function and Associated Uncertainties for High Precision Photometers at the NMISA	66
A.A. Gaertner, C. Bamber, L.P. Boivin, M. Chrysler	NRC Photometer Design for the Realization of a Luminous Intensity Scale	70
Session III	LED Measurement and Characterization Session Chair: A. Sperling	
W. Halbritter, W. Horak, W. Jordan	Measurement Requirements for the Characterization of Photobiological Hazards posed by the Optical Radiation of Lamps or LEDs	76
M. Tongsheng, Y. Jiandong, L. Li	A Retinal Radiance Meter	86
G. Brida, M.L. Rastello F. Saccomandi, F. Viarengo	Development of LED Calibration Facility at INRIM	92
P. Csuti, B. Kránicz, U. Krüger, J. Schanda, F. Schmidt	Photometric and Colorimetric Stability of LEDs	96
Y. Zong, Y. Ohno	New Practical Method for Measurement of High-Power LEDs	102
G. Brida, M.L. Rastello, F. Saccomandi, F. Viarengo	A Combined Method for Measuring Total Flux and Luminous Intensity of LEDs	107
S. Park, D.H. Lee, Y.W. Kim, H.P. Kim, S.N. Park	Study on the Total Luminous Flux Measurement of Surface-Emitting Light Sources Using an Integrating Sphere	111
F.W. Leuschner	Photometry and Colorimetry of White LED Cap Lamps for Mining	114
Session IV	Goniophotometers and other developments Session Chair: G. Sauter	
M. Shaw, T. Goodman	Goniospectroradiometric Characterisation of Light Sources	118
L. Junkai, W. Jianping, M. Tongsheng	A Novel Goniophotometer with Pursuit Mirror	124
K. Oshima, K. Ohkubo, S. Mishima	The New Idea for Total Luminous Flux Measurement	128
M.E. Nadal, G. Obein	NIST Goniospectrometer for Surface Color Measurements	134

Authors	Title	Page
E. Chorro, F. Martínez-Verdú, J. Campos, A. Pons	On the Importance of Rotating Metallic and Pearlescent Samples around the Normal in Multi-Gonio-Spectrophotometric Measurements	139
G.P. Eppeldauer, C.C. Miller, Y. Ohno	Detector-Based Calibration Procedures for Tristimulus Colorimeter Standards	141
J. Hartmann, K. Anhalt, R.D. Taubert	Towards a More Accurate and Reliable Source Based Radiometry and Photometry	147
Poster Session		
D.Barrios, R. Vergaz, J.M.S. Pena, C. Pozo J.A. Pomposo	Coloration, Voltage and Charge Density Relation of Viologens based Electrochromic Devices	152
D. Barrios, A.F.P. Román, R. Vergaz, J.I. Santos, J.M.S. Pena,	Chromatic Characterization of a RGB-LED Backlight System for an Antiferroelectric LCD *	157
U. Binder, W. Halbritter, W. Jordan, G. Sauter, W. Steudtner, N. Wagner	The New Hemispherical Robot Goniophotometer of the Central Laboratory for Light Measurements of OSRAM GmbH Munich	159
G. Bizjak, M.B. Kobav B. Luin	Measurement of Luminance of Symbols on Automotive Switches with Digital Camera	164
G. Bizjak, M. Prelovšek	Measurement of Variations of Correlated Color Temperature of White LEDs	170
K. Bredemeier, F. Schmidt	Ray Data Measurements of Modern Light Sources	176
G. Brida, M.L. Rastello	The Candela: Towards Quantum Photon-Based Standards	181
P.-T. Chou, S.-B. Huang, S.-P. Ying	Measurements for Near Field Source Models of LED Die using Source Imaging Goniometer	185
L. Hui, L. Yandouq, Chenzhu, X. Wenbin	Using Incandescent Lamps as Transfer Standards for Luminous Flux of Compact Fluorescent Lamps	189
O.P. Malanand *	Research of the Spectrocolorimetric Method Uncertainties for Chromaticity Coordinates Measurements *	193
I. Montford, C. Porrovecchio, M. Smid	Use of Switched Integrator Amplifier for High Accuracy Optical Measurements of Steady and Low Level Photocurrent Signals	195
C. Schwanengel	Fast Headlamp Measurement with Image Luminance Measurement Technique	197

* Extended Abstract (Full paper was not submitted)

Authors	Title	Page
M. Smid, G. Porrovecchio, R. Smid	Super Lineality: a Method to Improve the Linearity of a Switched Integrator Amplifier	202
K. Richter	Colour Management Reference Circle: Scan – File – Print – Scan using a CIELAB Camera and Standard Offset Printing	204
E.W.M. van der Ham, E. van Veldhoven, D.H.C.D Bos	Accurate f_1' Determination for Total Luminous Flux Measurements of High-Power LEDs beyond the 0,3% Level	210
E. Chorro, F. Martinez-Verdú J. Campos, A. Pons **	On the importance of rotating metallic and pearlescent samples around the normal in multi-gonio-spectrophotometric measurements **	A-1
LIST OF PARTIPANTS		213

** Addendum (Full paper was submitted after deadline)

KEYNOTE PAPER

GONIOPHOTOMETRY: NEW CHALLENGES AND NOVEL SOLUTIONS

Georg Sauter

Physikalisch-Technische Bundesanstalt, Braunschweig

1. INTRODUCTION

Goniophotometric measurements are carried out using three different geometries between the light source and the photometer: (i) large distance, to collect values of angular distributions of luminous intensity $I(\theta, \phi)$ by a photometer held in a fixed position, (ii) medium distance, to measure the pattern of illuminances $E(\vartheta, \varphi)$ on a fictitious envelope by moving a photometer and evaluation of luminous flux values with low uncertainty, (iii) short distance, to determine the angular distribution of luminance $L(x, y, \theta, \phi)$ for each element of the light emitting surface of the source by a moving imaging photometer.

The constructions of goniophotometers, calibration, data acquisition and principle models for an evaluation of the quantities are subject of this report. Gonioreflectometers for a determination of the indicatrix of reflectance are not included.

2. LUMINOUS INTENSITY

Today, the design for a lighting of spaces is evaluated from angular distribution of the luminous intensity $I(\theta, \phi)$ assigned to luminaires and sources. The angles $0 \leq \theta \leq \pi$, $0 \leq \phi \leq 2\pi$ are spherical coordinates $\{d, \theta, \phi\}$ of a Cartesian coordinate system attached to the source. Other plane-systems are also internationally agreed with denoted values of the angles to state the luminous intensity distribution in a defined format.

Luminous intensity is a property of a "point-like" source, which can be calculated from the illuminance even for sources with extended emitting areas or collimated beams, provided the distance is sufficiently large.

Only two types [1] of traditional goniophotometers perform large distance measurements. In any case, the photometer head is mounted in a fixed position with an arbitrary large distance to the source, while the latter is rotated about a vertical axis.

The simplest goniophotometer rotates sources additionally about a horizontal axis, which alters significantly the operational conditions and can change the luminous flux value and the relative intensity distribution, e.g. of LED-clusters or high-power LEDs. An additional photometer mechanically connected to the moving source sets a monitor to compensate for changes of the luminous flux values.

The hugest goniophotometer moves a large flat mirror around the horizontal axis and the photometer head measures only the reflected image of the source. The source is placed in the effective centre of the goniophotometer and rotates about a vertical axis. Different constructions have either the mirror or the source located on the horizontal axis and the holder of the one or the other is moved on a circle about this axis.

Measurements with these types of goniophotometers are time-consuming and yet only a minor part of the full solid angle is covered by a complete measurement (e.g. a photometer with aperture 15 mm radius in 15 m distance may measure at 10 000 positions and covers just 0.25 % of the full solid angle). Stray-light, polarization and spectral mismatch from the reflectance of the mirror increase the uncertainty associated to evaluated luminous flux values.

Usually, the luminous intensity distributions $I_x^*(\theta, \phi)$ of luminaires are listed in a "normalized" presentation: the values are stated for an internal source producing just 1000 lm.

$$I_x^*(\theta, \phi) = 1000 \cdot I_x(\theta, \phi) / \Phi_x \quad (1)$$

The luminous flux Φ_x emitted by the internal source during measurement of the luminous intensity distribution is determined by separate measurements or evaluated from the luminous intensity distribution $I_x(\theta, \phi)$ and the efficiency η of the luminaire.

$$\Phi_x = \frac{1}{\eta} \int_0^{2\pi} \int_0^\pi I_x(\theta, \phi) \sin \theta \partial \theta \partial \phi \quad (2)$$